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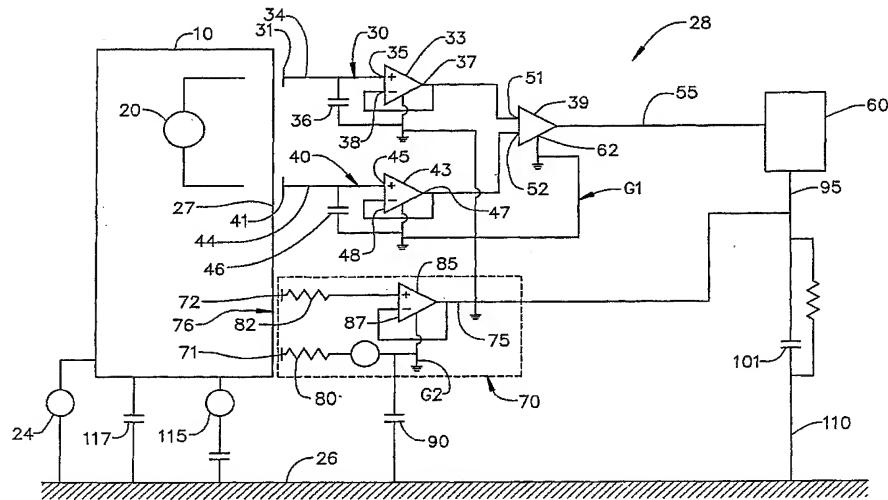
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(54) Title: A SENSOR SYSTEM FOR MEASURING AN ELECTRIC POTENTIAL SIGNAL OF AN OBJECT



(57) **Abstract:** The invention generally pertains to reducing artifact noise signals present when non-invasive capacitive-type signal measurements are taken of static electric fields produced by an object (10) of interest. According to a first preferred embodiment of the invention, a given static artifact signal is reduced by minimizing the potential difference between a ground point (G1) of sensor circuitry and the potential of the object (10). According to a second preferred embodiment of the invention, the change in signal due to motion of the sensor (30, 40, 40', 230, 330, 430, 530, 630) in the field produced by the object (10) is minimized by reducing the impact of changes in coupling to the signal source.

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